Si570/Si571



10 MHz to 1.4 GHz I²C Programmable XO/VCXO

Features

- Any programmable output frequencies from 10 to 945 MHz and select frequencies to 1.4 GHz
- I²C serial interface
- 3rd generation DSPLL[®] with superior jitter performance
- 3x better frequency stability than SAW-based oscillators

Applications

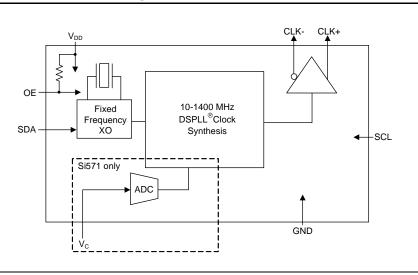
- SONET/SDH
- xDSL
- 10 GbE LAN/WAN
- ATE

- Internal fixed crystal frequency ensures high reliability and low aging
- Available LVPECL, CMOS, LVDS, and CML outputs
- Industry-standard 5x7 mm package
- Pb-free/RoHS-compliant
- 1.8, 2.5, or 3.3 V supply
- High performance instrumentation
- Low-jitter clock generation
- Optical modules
- Clock and data recovery

Description

The Si570 XO/Si571 VCXO utilizes Silicon Laboratories' advanced DSPLL[®] circuitry to provide a low-jitter clock at any frequency. The Si570/Si571 are userprogrammable to any output frequency from 10 to 945 MHz and select frequencies to 1400 MHz with <1 ppb resolution. The device is programmed via an I²C serial interface. Unlike traditional XO/VCXOs where a different crystal is required for each output frequency, the Si57x uses one fixed-frequency crystal and a DSPLL clock synthesis IC to provide any-frequency operation. This IC-based approach allows the crystal resonator to provide exceptional frequency stability and reliability. In addition, DSPLL clock synthesis provides superior supply noise rejection, simplifying the task of generating low-jitter clocks in noisy environments typically found in communication systems.

Functional Block Diagram





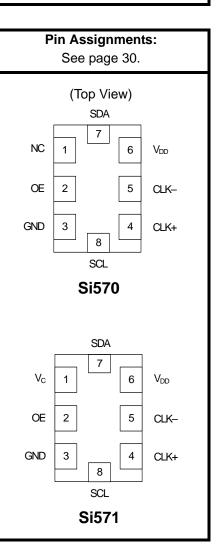


TABLE OF CONTENTS

Section

<u>Page</u>

1. Detailed Block Diagrams 2. Electrical Specifications	
3. Functional Description	
3.1. Programming a New Output Frequency	14
3.2. Si570 Programming Procedure	
3.3. Si570 Troubleshooting FAQ	
3.4. I ² C Interface	
4. Serial Port Registers	
5. Si570 (XO) Pin Descriptions	
6. Si571 (VCXO) Pin Descriptions	
7. Ordering Information	
8. Si57x Mark Specification	
9. Outline Diagram and Suggested Pad Layout	
10. 8-Pin PCB Land Pattern	
Revision History	



1. Detailed Block Diagrams

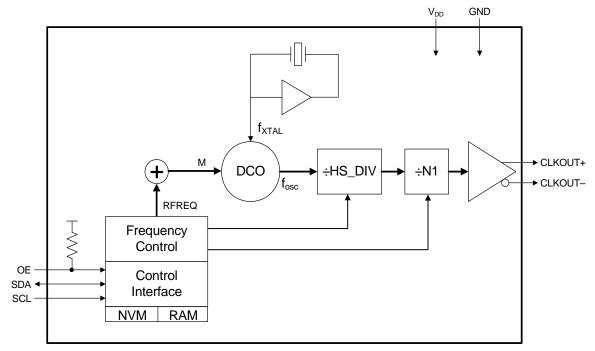


Figure 1. Si570 Detailed Block Diagram

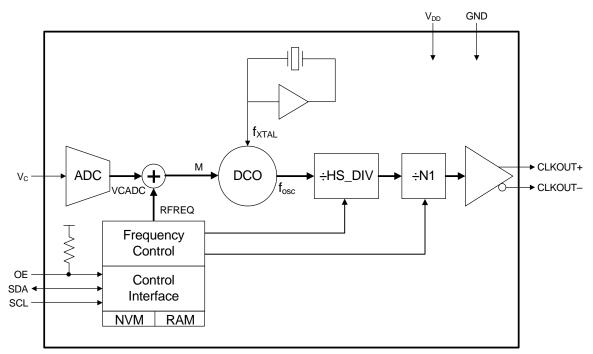


Figure 2. Si571 Detailed Block Diagram



2. Electrical Specifications

Table 1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
		3.3 V option	2.97	3.3	3.63	
Supply Voltage ¹	V _{DD}	2.5 V option	2.25	2.5	2.75	V
		1.8 V option	1.71	1.8	1.89	-
Supply Current	I _{DD}	Output enabled LVPECL CML LVDS CMOS TriState mode		120 108 99 90 60	130 117 108 98 75	mA
Output Enable (OE) ² , Serial Data (SDA), Serial Clock (SCL)		V _{IH} V _{IL}	0.75 x V _{DD}	_	— 0.5	v
Operating Temperature Range	T _A		-40	_	85	°C

1. Selectable parameter specified by part number. See Section "7. Ordering Information" on page 31 for further details.

2. OE pin includes a 17 k Ω pullup resistor to V_DD. See "7.Ordering Information".

Table 2. V_C Control Voltage Input (Si571)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Control Voltage Tuning Slope ^{1,2,3}	κ _v	V_{C} 10 to 90% of V_{DD}	_	33 45 90 135 180 356	_	ppm/V
Control Voltage Linearity ⁴	Lue	BSL	-5	±1	+5	%
Control voltage Linearity	L _{VC}	Incremental	-10	±5	+10	/0
Modulation Bandwidth	BW		9.3	10.0	10.7	kHz
V _C Input Impedance	Z _{VC}		500	—	_	kΩ
Nominal Control Voltage ⁵	V _{CNOM}	@ f _O	—	V _{DD} /2	_	V
Control Voltage Tuning Range	V _C		0		V _{DD}	V

Notes:

1. Positive slope; selectable option by part number. See "7. Ordering Information" on page 31.

For best jitter and phase noise performance, always choose the smallest K_V that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (K_V), Stability, and Absolute Pull Range (APR)" for more information.
 K_V variation is ±10% of typical values.

BSL determined from deviation from best straight line fit with V_C ranging from 10 to 90% of V_{DD}. Incremental slope is determined with V_C ranging from 10 to 90% of V_{DD}.

determined with V_C ranging from 10 to 90% of V_{DD}. 5. Nominal output frequency set by V_{CNOM} = $1/2 \times V_{DD}$.



Table 3. CLK± Output Frequency Characteristics

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Programmable Frequency	£	LVPECL/LVDS/CML	10		1417.5	
Range ^{1,2}	f _O	CMOS	10		160	MHz
			-7		7	
To some operations. Other bills 1.3		$T = 40 t_{0} + 85 0$	-20	—	+20	
Temperature Stability ^{1,3}		T _A = −40 to +85 °C	-50	—	+50	ppm
			-100		+100	
Initial Accuracy			_	1.5	—	ppm
A .	¢	Frequency drift over first year	_	_	±3	ppm
Aging	f _a	Frequency drift over 20-year life	_		±10	ppm
		Temp stability = ±7 ppm	_		±20	ppm
Total Stability		Temp stability = ±20 ppm	_		±31.5	ppm
		Temp stability = ±50 ppm			±61.5	ppm
Absolute Pull Range ^{1,3}	APR		±12	_	±375	ppm
Power up Time ⁴	tosc		_	_	10	ms
Notes: 1. See Section "7. Ordering I	nformation" or	n page 31 for further details. r. Three speed grades available:				

Grade A covers 10 to 945 MHz, 970 to 1134 MHz, and 1213 to 1417.5 MHz. Grade B covers 10 to 810 MHz. Grade C covers 10 to 280 MHz.

- Selectable parameter specified by part number.
 Time from power up or tristate mode to f_O.



Table 4. CLK± Output Levels and Symmetry

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
	Vo	mid-level	V _{DD} – 1.42	_	V _{DD} – 1.25	V
LVPECL Output Option ¹	V _{OD}	swing (diff)	1.1	—	1.9	V _{PP}
	V _{SE}	swing (single-ended)	0.55	—	0.95	V _{PP}
LVDS Output Option ²	V _O	mid-level	1.125	1.20	1.275	V
	V _{OD}	swing (diff)	0.5	0.7	0.9	V_{PP}
	V.	2.5/3.3 V option mid-level	_	V _{DD} - 1.30		V
CML Output Option ²	Vo	1.8 V option mid-level	—	V _{DD} – 0.36		V
	V	2.5/3.3 V option swing (diff)	1.10	1.50	1.90	V_{PP}
	V _{OD}	1.8 V option swing (diff)	0.35	0.425	0.50	V_{PP}
	V _{OH}	I _{OH} = 32 mA	0.8 x V _{DD}	—	V _{DD}	V
CMOS Output Option ³	V _{OL}	I _{OL} = 32 mA	—	—	0.4	V
		LVPECL/LVDS/CML	_	_	350	ps
Rise/Fall time (20/80%)	t _{R,} t _F	CMOS with $C_L = 15 \text{ pF}$	—	1		ns
Symmetry (duty cycle)	SYM	LVPECL: V _{DD} - 1.3 V (diff) LVDS: 1.25 V (diff) CMOS: V _{DD} /2	45	_	55	%
Notes: 1. R _{term} = 50 Ω to V _{DD} – 2. R _{term} = 100 Ω (different		L	1	L	<u> </u>	

2. $R_{term} = 100 \Omega$ (differential). 3. $C_L = 15 \text{ pF}$



Table 5. CLK± Output Phase Jitter (Si570)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Phase Jitter (RMS) ¹	фJ	12 kHz to 20 MHz (OC-48)		0.25	0.40	ps
for $F_{OUT} \ge 500 \text{ MHz}$		50 kHz to 80 MHz (OC-192)	_	0.26	0.37	
Phase Jitter (RMS) ¹	фJ	12 kHz to 20 MHz (OC-48)		0.36	0.50	ps
for F _{OUT} of 125 to 500 MHz		50 kHz to 80 MHz (OC-192) ²	—	0.34	0.42	
Phase Jitter (RMS)	фJ	12 kHz to 20 MHz (OC-48) ²		0.62		ps
for F _{OUT} of 10 to 160 MHz CMOS Output Only		50 kHz to 20 MHz ²		0.61	_	
 Notes: 1. Refer to AN256 for further infe 2. Max offset frequencies: 80 MHz for FOUT ≥ 250 MHz 20 MHz for 50 MHz ≤ FOUT < 2 MHz for 10 MHz ≤ FOUT < 	<250 MHz					



Table 6. CLK± Output Phase Jitter (Si571)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Phase Jitter (RMS) ^{1,2,3}	фJ	Kv = 33 ppm/V				ps
for F _{OUT} ≥ 500 MHz		12 kHz to 20 MHz (OC-48)	—	0.26	—	
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 45 ppm/V				
		12 kHz to 20 MHz (OC-48)	—	0.27	—	
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 90 ppm/V				
		12 kHz to 20 MHz (OC-48)	—	0.32	—	
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 135 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.40	—	
		50 kHz to 80 MHz (OC-192)	—	0.27	—	
		Kv = 180 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.49	—	
		50 kHz to 80 MHz (OC-192)	—	0.28	—	
		Kv = 356 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.87	—	
		50 kHz to 80 MHz (OC-192)	—	0.33	—	
Notes:	1			1	1	

Differential Modes: LVPECL/LVDS/CML. Refer to AN255, AN256, and AN266 for further information.

For best jitter and phase noise performance, always choose the smallest K_V that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)" for more information.

3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply rejection (PSR) advantage of Si55x versus SAW-based solutions.

4. Single ended mode: CMOS. Refer to the following application notes for further information: "AN255: Replacing 622 MHz VCSO Devices with the Si55x VCXO"
"AN256: Integrated Phase Noise"
"AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)"
5. Magnetic for the supervision

5. Max offset frequencies: 80 MHz for $F_{OUT} \ge 250$ MHz 20 MHz for 50 MHz $\le F_{OUT} <250$ MHz 2 MHz for 10 MHz $\le F_{OUT} <50$ MHz.



Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Phase Jitter (RMS) ^{2,4,5}	φJ	Kv = 33 ppm/V				ps
for F _{OUT} 10 to 160 MHz		12 kHz to 20 MHz (OC-48)	_	0.63	_	
CMOS Output Only		50 kHz to 20 MHz	—	0.62	—	
		Kv = 45 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.63	—	
		50 kHz to 20 MHz	—	0.62	—	
		Kv = 90 ppm/V				
		12 kHz to 20 MHz (OC-48)	—	0.67	—	
		50 kHz to 20 MHz	—	0.66	—	
		Kv = 135 ppm/V				
		12 kHz to 20 MHz (OC-48)	—	0.74	—	
		50 kHz to 20 MHz	—	0.72	—	
		Kv = 180 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.83	—	
		50 kHz to 20 MHz	—	0.8	—	
		Kv = 356 ppm/V				1
		12 kHz to 20 MHz (OC-48)	—	1.26	—	
		50 kHz to 20 MHz	_	1.2		

Table 6. CLK± Output Phase Jitter (Si571) (Continued)

1. Differential Modes: LVPECL/LVDS/CML. Refer to AN255, AN256, and AN266 for further information.

2. For best jitter and phase noise performance, always choose the smallest K_V that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)" for more information.

3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply rejection (PSR) advantage of Si55x versus SAW-based solutions.

4. Single ended mode: CMOS. Refer to the following application notes for further information: "AN255: Replacing 622 MHz VCSO Devices with the Si55x VCXO" "AN256: Integrated Phase Noise" "AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)"
5. Max offset frequencies:

80 MHz for $F_{OUT} \ge 250$ MHz 20 MHz for 50 MHz $\le F_{OUT} < 250$ MHz 2 MHz for 10 MHz $\le F_{OUT} < 50$ MHz.



Table 6. CLK± Output Phase Jitter (Si571) (Continued)

	Symbol	Test Condition	Min	Тур	Max	Unit			
Phase Jitter (RMS) ^{1,2,3,5}	фJ	Kv = 33 ppm/V				ps			
for F _{OUT} of 125 to		12 kHz to 20 MHz (OC-48)	_	0.37	_				
500 MHz		50 kHz to 80 MHz (OC-192)	—	0.33	—				
		Kv = 45 ppm/V							
		12 kHz to 20 MHz (OC-48)	_	0.37	_				
		50 kHz to 80 MHz (OC-192)	—	0.33	—				
		Kv = 90 ppm/V							
		12 kHz to 20 MHz (OC-48)	_	0.43	—				
	50 kHz	50 kHz to 80 MHz (OC-192)	—	0.34	—				
		Kv = 135 ppm/V							
		12 kHz to 20 MHz (OC-48)	_	0.50	_				
		50 kHz to 80 MHz (OC-192)	—	0.34	—				
		Kv = 180 ppm/V							
		12 kHz to 20 MHz (OC-48)	_	0.59	_				
					50 kHz to 80 MHz (OC-192)	—	0.35	—	
		Kv = 356 ppm/V							
		12 kHz to 20 MHz (OC-48)	_	1.00	_				
		50 kHz to 80 MHz (OC-192)	—	0.39	—				
		CML. Refer to AN255, AN256, and A prmance, always choose the smallest				1			

requirements. See "AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)" for more information.

3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply rejection (PSR) advantage of Si55x versus SAW-based solutions.

4. Single ended mode: CMOS. Refer to the following application notes for further information: "AN255: Replacing 622 MHz VCSO Devices with the Si55x VCXO" "AN256: Integrated Phase Noise" "AN266: VCXO Tuning Slope (kV), Stability, and Absolute Pull Range (APR)" 5. Max offset frequencies:

80 MHz for $\mathrm{F}_{\mathrm{OUT}}$ \geq 250 MHz 20 MHz for 50 MHz \leq F_{OUT} <250 MHz 2 MHz for 10 MHz \leq F_{OUT} <50 MHz.

Table 7. CLK± Output Period Jitter

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit		
Dariad littar*	J _{PER}	RMS	_	2	—	ne		
Period Jitter*		Peak-to-Peak	—	14	—	ps		
*Note: Any output mode, including CMOS, LVPECL, LVDS, CML. N = 1000 cycles. Refer to "AN279: Estimating Period Jitter from Phase Noise" for further information.								



-121

-134

-146

-148

Unit

dBc/Hz

,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,										
Offset Frequency (f)	120.00 MHz LVDS	156.25 MHz LVPECL	622.08 MHz LVPECL							
100 Hz	-112	-105	-97							
1 kHz	-122	-122	-107							
10 kHz	-132	-128	-116							

-137

-144

-150

n/a

Table 8. Typical CLK± Output Phase Noise (Si570)

Table 9. Typical CLK± Output Phase Noise (Si571)

100 kHz

1 MHz

10 MHz

100 MHz

Offset Frequency (f)	74.25 MHz 90 ppm/V LVPECL	491.52 MHz 45 ppm/V LVPECL	622.08 MHz 135 ppm/V LVPECL	Unit
100 Hz	-87	-75	-65	
1 kHz	-114	-100	-90	
10 kHz	-132	-116	-109	
100 kHz	-142	-124	-121	dBc/Hz
1 MHz	-148	-135	-134	
10 MHz	-150	-146	-146	
100 MHz	n/a	-147	-147	

-135

-144

-147

n/a

Table 10. Environmental Compliance

(The Si570/571 meets the following qualification test requirements.)

Parameter	Conditions/Test Method
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross and Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level	J-STD-020, MSL1
Contact Pads	Gold over Nickel



Table 11. Programming Constraints and Timing (V_{DD} = 3.3 V $\pm 10\%,$ T_A = -40 to 85 °C)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
		$HS_DIV \times N1 > = 6$	10		945	MHz
Output Frequency Range	СКО _F	HS_DIV = 5 N1 = 1	970	—	1134	MHz
		HS_DIV = 4 N1 = 1	1.2125	_	1.4175	GHz
Frequency Reprogramming Resolution	M _{RES}	f _{xtal} = 114.285 MHz	_	0.09	_	ppb
Internal Oscillator Frequency	f _{OSC}		4850	—	5670	MHz
Internal Crystal Frequency Accuracy	f _{XTAL}	Maximum variation is ±2000 ppm	_	114.285	—	MHz
Delta Frequency for Continuous Output		From center frequency	-3500	—	+3500	ppm
Unfreeze to NewFreq Timeout			_	—	10	ms
Settling Time for Small Frequency Change		<±3500 ppm from center frequency	_	_	100	μs
Settling Time for Large Frequency Change		>±3500 ppm from center frequency after setting NewFreq bit	_	—	10	ms

Table 12. Thermal Characteristics

(Typical values TA = 25 °C, V_{DD} = 3.3 V)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Thermal Resistance Junction to Ambient	θ_{JA}	Still Air	—	84.6	_	°C/W
Thermal Resistance Junction to Case	θJC	Still Air	—	38.8	_	°C/W
Ambient Temperature	T _A		-40	_	85	°C
Junction Temperature	Т _Ј			_	125	°C



Table 13. Absolute Maximum Ratings^{1,2}

Parameter	Symbol	Rating	Unit
Supply Voltage, 1.8 V Option	V _{DD}	-0.5 to +1.9	V
Supply Voltage, 2.5/3.3 V Option	V _{DD}	-0.5 to +3.8	V
Input Voltage	VI	-0.5 to V _{DD} + 0.3	V
Storage Temperature	Τ _S	-55 to +125	٥C
ESD Sensitivity (HBM, per JESD22-A114)	ESD	>2000	V
Soldering Temperature (Lead-free Profile)	T _{PEAK}	260	٥C
Soldering Temperature Time @ T _{PEAK} (Lead-free Profile)	t _P	20–40	seconds
Netes			

Notes:

1. Stresses beyond the absolute maximum ratings may cause permanent damage to the device. Functional operation or specification compliance is not implied at these conditions.

2. The device is compliant with JEDEC J-STD-020. Refer to packaging FAQ available for download at www.siliconlabs.com/VCXO for further information, including soldering profiles.



3. Functional Description

The Si570 XO and the Si571 VCXO are low-jitter oscillators ideally suited for applications requiring programmable frequencies. The Si57x can be programmed to generate virtually any output clock in the range of 10 MHz to 1.4 GHz. Output jitter performance complies with and exceeds the strict requirements of high-speed communication systems including OC-192/STM-64 and 10 Gigabit Ethernet (10 GbE).

The Si57x consists of a digitally-controlled oscillator (DCO) based on Silicon Laboratories' third-generation DSPLL technology, which is driven by an internal fixed-frequency crystal reference.

The device's default output frequency is set at the factory and can be reprogrammed through the two-wire I^2C serial port. Once the device is powered down, it will return to its factory-set default output frequency.

While the Si570 outputs a fixed frequency, the Si571 has a pullable output frequency using the voltage control input pin. This makes the Si571 an ideal choice for high-performance, low-jitter, phase-locked loops.

3.1. Programming a New Output Frequency

The output frequency (f_{out}) is determined by programming the DCO frequency (f_{DCO}) and the device's output dividers (HS_DIV, N1). The output frequency is calculated using the following equation:

$$f_{out} = \frac{f_{DCO}}{Output \text{ Dividers}} = \frac{f_{XTAL} \times RFREQ}{HSDIV \times N1}$$

The DCO frequency is adjustable in the range of 4.85 to 5.67 GHz by setting the high-resolution 38-bit fractional multiplier (RFREQ). The DCO frequency is the product of the internal fixed-frequency crystal (f_{XTAL}) and RFREQ.

The 38-bit resolution of RFREQ allows the DCO frequency to have a programmable frequency resolution of 0.09 ppb.

As shown in Figure 3, the device allows reprogramming of the DCO frequency up to ± 3500 ppm from the center frequency configuration without interruption to the output clock. Changes greater than the ± 3500 ppm window will cause the device to recalibrate its internal tuning circuitry, forcing the output clock to momentarily stop and start at any arbitrary point during a clock cycle. This re-calibration process establishes a new center frequency and can take up to 10 ms. Circuitry receiving a clock from the Si57x device that is sensitive to glitches or runt pulses may have to be reset once the recalibration process is complete.

3.1.1. Reconfiguring the Output Clock for a Small Change in Frequency

For output changes less than ± 3500 ppm from the center frequency configuration, the DCO frequency is the only value that needs reprogramming. Since $f_{DCO} = f_{XTAL} \times RFREQ$, and that f_{XTAL} is fixed, changing the DCO frequency is as simple as reconfiguring the RFREQ value as outlined below:

- Using the serial port, read the current RFREQ value (addresses 7–12 for all Si571 devices and Si570 devices with 20 ppm and 50 ppm temperature stability; or addresses 13–18 for Si570 devices with 7 ppm temperature stability).
- 2. Calculate the new value of RFREQ given the change in frequency.

$$RFREQ_{new} = RFREQ_{current} \times \frac{f_{out_new}}{f_{out_current}}$$

3. Using the serial port, write the new RFREQ value (addresses 7–12 for all Si571 devices and Si570 devices with 20 ppm and 50 ppm temperature stability; or addresses 13–18 for Si570 devices with 7 ppm temperature stability).

Example:

An Si570 generating a 148.35 MHz clock must be reconfigured "on-the-fly" to generate a 148.5 MHz clock. This represents a change of +1011.122 ppm, which is well within the \pm 3500 ppm window.

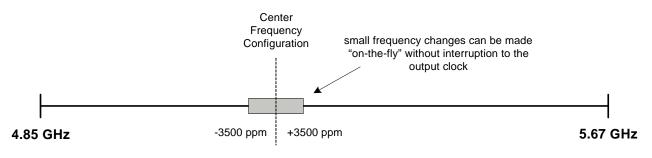


Figure 3. DCO Frequency Range



A typical frequency configuration for this example:

RFREQ_{current} = 0x2EBB04CE0

F_{out_current} = 148.35 MHz

 $F_{out new} = 148.50 \text{ MHz}$

Calculate RFREQ_{new} to change the output frequency from 148.35 MHz to 148.5 MHz:

$$\mathsf{RFREQ}_{\mathsf{new}} = 0x2\mathsf{EBB04CE0} \times \frac{148.50 \text{ MHz}}{148.35 \text{ MHz}}$$

= 0x2EC71D666

Note: Performing calculations with RFREQ requires a minimum of 38-bit arithmetic precision.

Even relatively small changes in output frequency may require writing more than 1 RFREQ register. Such multiregister RFREQ writes can impact the output clock frequency on a register-by-register basis during updating.

Interim changes to the output clock during RFREQ writes can be prevented by using the following procedure:

1. Freeze the "M" value (Set Register 135 bit 5 = 1).

2. Write the new frequency configuration (RFREQ).

3. Unfreeze the "M" value (Set Register 135 bit 5 = 0)

3.1.2. Reconfiguring the Output Clock for Large Changes in Output Frequency

For output frequency changes outside of ± 3500 ppm from the center frequency, it is likely that both the DCO frequency and the output dividers need to be reprogrammed. Note that changing the DCO frequency outside of the ± 3500 ppm window will cause the output to momentarily stop and restart at any arbitrary point in a clock cycle. Devices sensitive to glitches or runt pulses may have to be reset once reconfiguration is complete.

The process for reconfiguring the output frequency outside of a ±3500 ppm window first requires reading the current RFREQ, HSDIV, and N1 values. Next, calculate fXTAL for the device. Note that, due to slight variations of the internal crystal frequency from one device to another, each device may have a different RFREQ value or possibly even different HSDIV or N1 values to maintain the same output frequency. It is necessary to calculate fXTAL for each device. Third, write the new values back to the device using the appropriate registers (addresses 7-12 for all Si571 devices and Si570 devices with 20 ppm and 50 ppm temperature stability; or addresses 13-18 for Si570 devices with 7 ppm temperature stability) sequencing as described in "3.1.2.1.Writing the New Frequency Configuration".

$$f_{XTAL} = \frac{F_{out} \times HSDIV \times N1}{RFREQ}$$

Once f_{XTAL} has been determined, new values for RFREQ, HSDIV, and N1 are calculated to generate a new output frequency (f_{out_new}). New values can be calculated manually or with the Si57x-EVB software, which provides a user-friendly application to help find the optimum values.

The first step in manually calculating the frequency configuration is to determine new frequency divider values (HSDIV, N1). Given the desired output frequency (fout_new), find the frequency divider values that will keep the DCO oscillation frequency in the range of 4.85 to 5.67 GHz.

$$f_{DCO_new} = f_{out_new} \times HSDIV_{new} \times N1_{new}$$

Valid values of HSDIV are 4, 5, 6, 7, 9 or 11. N1 can be selected as 1 or any even number up to 128 (i.e. 1, 2, 4, 6, 8, 10 ... 128). To help minimize the device's power consumption, the divider values should be selected to keep the DCO's oscillation frequency as low as possible. The lowest value of N1 with the highest value of HS_DIV also results in the best power savings.

Once HS_DIV and N1 have been determined, the next step is to calculate the reference frequency multiplier (RFREQ).

$$\mathsf{RFREQ}_{\mathsf{new}} = \frac{\mathsf{f}_{\mathsf{DCO_new}}}{\mathsf{f}_{\mathsf{XTAL}}}$$

RFREQ is programmable as a 38-bit binary fractional frequency multiplier with the first 10 most significant bits (MSBs) representing the integer portion of the multiplier, and the 28 least significant bits (LSBs) representing the fractional portion.

Before entering a fractional number into the RFREQ register, it must be converted to a 38-bit integer using a bitwise left shift operation by 28 bits, which effectively multiplies RFREQ by 2^{28} .

Example:

RFREQ = 46.043042064d

Multiply RFREQ by $2^{28} = 12359584992.1$

Discard the fractional portion = 12359584992

Convert to hexadecimal = 02E0B04CE0h

In the example above, the multiplication operation requires 38-bit precision. If 38-bit arithmetic precision is not available, then the fractional portion can be separated from the integer and shifted to the left by 28-bits. The result is concatenated with the integer portion



to form a full 38-bit word. An example of this operation is shown in Figure 4.

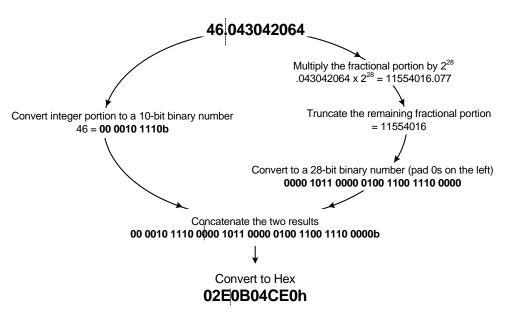


Figure 4. Example of RFREQ Decimal to Hexadecimal Conversion

3.1.2.1. Writing the New Frequency Configuration

Once the new values for RFREQ, HSDIV, and N1 are determined, they can be written directly into the device from the serial port using the following procedure:

- 1. Freeze the DCO (bit 4 of Register 137)
- Write the new frequency configuration (RFREQ, HSDIV, and N1) to addresses 7–12 for all Si571 devices and Si570 devices with 20 ppm and 50 ppm temperature stability; or addresses 13–18 for Si570 devices with 7 ppm temperature stability.
- 3. Unfreeze the DCO and assert the NewFreq bit (bit 6 of Register 135) within the maximum Unfreeze to NewFreq Timeout specified in Table 11, "Programming Constraints and Timing," on page 12.

The process of freezing and unfreezing the DCO will cause the output clock to momentarily stop and start at any arbitrary point during a clock cycle. This process can take up to 10 ms. Circuitry that is sensitive to glitches or runt pulses may have to be reset after the new frequency configuration is written.

Example:

An Si570 generating 156.25 MHz must be re-configured to generate a 161.1328125 MHz clock (156.25 MHz x 66/ 64). This frequency change is greater than ±3500 ppm.

f_{out} = 156.25 MHz

Read the current values for RFREQ, HS_DIV, N1:

 $RFREQ_{current} = 0x2BC011EB8h = 11744124600d, 11744124600d x 2^{28} = 43.7502734363d$ HS_DIV = 4

N1 = 8

Calculate f_{XTAL}, f_{DCO_current}

 $f_{DCO, current} = f_{out} \times HSDV \times N1 = 5.00000000 GHz$

$$f_{XTAL} = \frac{f_{DCO_current}}{RFREQ_{current}} = 114.285 \text{ MHz}$$



Given $f_{out_new} = 161.1328125$ MHz, choose output dividers that will keep f_{DCO} within the range of 4.85 to 5.67 GHz. In this case, keeping the same output dividers will still keep f_{DCO} within its range limits:

$$\begin{split} f_{DCO_new} &= f_{out_new} \times HSDV_{new} \times N1_{new} \\ &= 161.1328125 \text{ MHz} \times 4 \times 8 = 5.156250000 \text{ GHz} \end{split}$$

Calculate the new value of RFREQ given the new DCO frequency:

 $RFREQ_{new} = \frac{f_{DCO_new}}{f_{XTAL}} = 45.11746948$ = 0x2D1E127AD



3.2. Si570 Programming Procedure

This following example was generated using *Si514/70/71/98/99 Programmable Oscillator Software* V4.0.1 found under the **Tools** tab at the following web page.

http://www.siliconlabs.com/products/clocksoscillators/oscillators/Pages/i2c-oscillator.aspx

On that same web page, the AN334 Si57x I2C XO/VCXO ANSI C Reference Design contains example C code for calculating register settings on the fly.

1. Read start-up frequency configuration (RFREQ, HS_DIV, and N1) from the device after power-up or register reset.

```
Registers for the Current Configuration
 Register
            Data
     7
              0x01
     8
              0xC2
     9
              0xBC
    10
              0x01
    11
              0x1E
    12
              0xB8
 RFREO = 0x2BC011EB8
        = 0x2BC011EB8 / (2^28) = 43.75027344
 HS_DIV = 0x0 = 4
 Ν1
        = 0x7 = 8
```

2. Calculate the actual nominal crystal frequency where f0 is the start-up output frequency.

fxtal = (f0 x HS_DIV x N1) / RFREQ
= (156.25000000 MHz x 4 x 8) / 43.750273436
= 114.285000000 MHz

3. Choose the new output frequency (f1).

Output Frequency (f1) = 161.132812000 MHz

Choose the output dividers for the new frequency configuration (HS_DIV and N1) by ensuring the DCO oscillation frequency (fdco) is between 4.85 GHz and 5.67 GHz where fdco = f1 x HS_DIV x N1. See the Divider Combinations tab for more options.

HS_DIV = 0x0 = 4 N1 = 0x7 = 8 fdco = f1 x HS_DIV x N1 = 161.132812000 MHz x 4 x 8 = 5.156249984 GHz



5. Calculate the new crystal frequency multiplication ratio (RFREQ) as RFREQ = fdco / fxtal

```
RFREQ = fdco / fxtal
= 5.156249984 GHz / 114.285000000 MHz
= 45.11746934
= 45.11746934 x (2^28) = 0x2D1E12788
```

- 6. Freeze the DCO by setting Freeze DCO = 1 (bit 4 of register 137).
- 7. Write the new frequency configuration (RFREQ, HS_DIV, and N1)

```
Registers for the New Configuration
Register Data
7 0x01
8 0xC2
9 0xD1
10 0xE1
11 0x27
12 0x88
```

8. Unfreeze the DCO by setting Freeze DCO = 0 and assert the NewFreq bit (bit 6 of register 135) within 10 ms.



3.3. Si570 Troubleshooting FAQ

1. Is the I²C bus working correctly and using the correct I²C address?

Probing the device I²C pins with an oscilloscope can sometimes reveal signal integrity problems. Si570/Si571 I²C communication is normally very robust, so if other devices on the I²C bus are communicating successfully, then the Si570/Si571 should also work.

You can confirm the specific I²C address expected by an Si570/Si571 device by using the part number lookup utility available on the Silicon Laboratories web site.

http://www.silabs.com/custom-timing

2. Is the correct register bank being written based on device stability?

Si570/Si571 devices use different configuration registers for 7 ppm temperature stability devices than they do for 20 ppm or 50 ppm temperature stability devices. The temperature stability of a Si570/Si571 device can be confirmed using the part number lookup utility available on the Silicon Laboratories web site or by referencing the 2nd ordering option code in the part number.

http://www.silabs.com/custom-timing

2nd Ordering Option Code:

A : 50 ppm temperature stability, 61.5 ppm total stability => Configuration Registers 7-12

B : 20 ppm temperature stability, 31.5 ppm total stability => Configuration Registers 7-12

C : 7 ppm temperature stability, 20 ppm total stability => Configuration Registers 13-18

3. Is the part-to-part variation in FXTAL included in calculations?

It is required that one determine the internal crystal frequency for each individual part before calculating a new output frequency. The procedure for determining the internal crystal frequency from the register values of a device is described elsewhere in this data sheet. See Section 3.2.

FXTAL = (FOUT x HSDIV x N1) / RFREQ <= note that RFREQ used here is the register value divided by 2^{28}

It is a common error to calculate the internal crystal frequency for one device and then use that same crystal frequency for all later devices. This will lead to offset errors in the output frequency accuracy from part-to-part. The internal crystal frequency must be calculated for each individual device.

4. Is the Unfreeze to NewFreq timeout spec being exceeded?

The Si570/Si571 requires the DCO to be 'frozen' when changing register values and then 'unfrozen' and a calibration initiated by writing the 'NewFreq' bit to restart it properly. If the 'unfreeze' and 'NewFreq' writes are delayed by 10 ms or more, the internal state machine can timeout and cause the configuration to revert to default values.

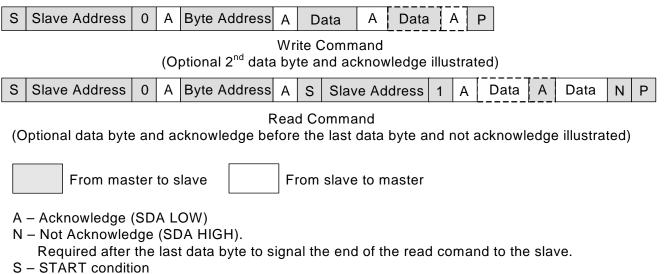
This 'unfreeze' and 'NewFreq' timing requirement is not usually a problem since the writes are done back-to-back, but if there is an interrupt or other system delay that may cause this 10 ms timing to be exceeded, it should be considered as a possible source of issues reprogramming the Si570/Si571.



3.4. I²C Interface

The control interface to the Si570 is an I^2 C-compatible 2-wire bus for bidirectional communication. The bus consists of a bidirectional serial data line (SDA) and a serial clock input (SCL). Both lines must be connected to the positive supply via an external pullup. Fast mode operation is supported for transfer rates up to 400 kbps as specified in the I^2 C-Bus Specification standard.

Figure 5 shows the command format for both read and write access. Data is always sent MSB. Data length is 1 byte. Read and write commands support 1 or more data bytes as illustrated. The master must send a Not Acknowledge and a Stop after the last read data byte to terminate the read command. The timing specifications and timing diagram for the I^2C bus can be found in the I^2C -Bus Specification standard (fast mode operation). The device I^2C address is specified in the part number.



P – STOP condition

Figure 5. I²C Command Format



4. Serial Port Registers

Note: Any register not listed here is reserved and must not be written. All bits are R/W unless otherwise noted.

Register	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
7	High Speed/ N1 Dividers	F	IS_DIV[2:0]		l	N1[6:2]		
8	Reference Frequency	N1[1:0]		RFREQ[37:32]				
9	Reference Frequency				RFREQ[31:24]				
10	Reference Frequency		RFREQ[23:16]						
11	Reference Frequency		RFREQ[15:8]						
12	Reference Frequency		RFREQ[7:0]						
13	High Speed/ N1 Dividers	HS_	DIV_7PPM	[2:0]	N1_7PPM[6:2]				
14	Reference Frequency	N1_7PI	PM[1:0]		RFREQ_7PPM[37:32]				
15	Reference Frequency			l	RFREQ_7F	PPM[31:24]]		
16	Reference Frequency			I	RFREQ_7F	PPM[23:16]			
17	Reference Frequency				RFREQ_7	PPM[15:8]			
18	Reference Frequency				RFREQ_7PPM[7:0]				
135	Reset/Freeze/ Memory Control	RST_REG	NewFreq	Freeze M	Freeze VCADC				RECALL
137	Freeze DCO		1	1	Freeze DCO				1



Register 7. High Speed/N1 Dividers

Bit	D7	D6	D5	D4 D3 D2 D1 D0					
Name		HS_DIV[2:0]		N1[6:2]					
Туре		R/W				R/W			

Bit	Name	Function
7:5	HS_DIV[2:0]	DCO High Speed Divider. Sets value for high speed divider that takes the DCO output f_{OSC} as its clock input. 000 = 4 001 = 5 010 = 6 011 = 7 100 = Not used. 101 = 9 110 = Not used. 111 = 11
4:0	N1[6:2]	CLKOUT Output Divider. Sets value for CLKOUT output divider. Allowed values are [1] and [2, 4, 6,, 2^7]. Illegal odd divider values will be rounded up to the nearest even value. The value for the N1 register can be calculated by taking the divider ratio minus one. For example, to divide by 10, write 0001001 (9 decimal) to the N1 registers. 0000000 = 1 1111111 = 2^7

Register 8. Reference Frequency

Bit	D7	D6	D5	D4	D3	D2	D1	D0	
Name	N1[1:0]	RFREQ[37:32]						
Туре	R/	W	R/W						

Bit	Name	Function
7:6	N1[1:0]	CLKOUT Output Divider. Sets value for CLKOUT output divider. Allowed values are $[1, 2, 4, 6,, 2^7]$. Illegal odd divider values will be rounded up to the nearest even value. The value for the N1 register can be calculated by taking the divider ratio minus one. For example, to divide by 10, write 0001001 (9 decimal) to the N1 registers. 0000000 = 1 1111111 = 2^7
5:0	RFREQ[37:32]	Reference Frequency. Frequency control input to DCO.



Register 9. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0											
Name	,	RFREQ[31:24]											
Туре		R/W											
Bit	Name				Functio	on							
7:0	RFREQ[31:24	RFREQ[31:24] Reference Frequency. Frequency control input to DCO.											

Register 10. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0									
Name	•	RFREQ[23:16]									
Туре		R/W									
Bit	Name Function										
7:0	RFREQ[23:1	Q[23:16] Reference Frequency.									
		_	Frequency control input to DCO.								

Register 11. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0									
Name	9	RFREQ[15:8]									
Туре	e R/W										
Bit	Name				Functior)					
7:0	RFREQ[15:8]	Reference Frequency.Frequency control input to DCO.									



Register 12. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0									
Name		RFREQ[7:0]									
Туре		R/W									
Bit	Name				Function)					
7:0	RFREQ[7:0]	RFREQ[7:0] Reference Frequency. Frequency control input to DCO.									

Register 13. High Speed/N1 Dividers

	-1	r	1	1	1	1	r.	,	
Bit	D7	D6	D5	D4	D3	D2	D1	D0	
Name	HS	_DIV_7PPM[2:0]	N1_7PPM[6:2]					
Туре		R/W				R/W			
Bit	Name				Functio	n			
7:5	HS_DIV_7PPI	Sets v 000 = 001 = 010 = 100 = 101 =	4 5 6 7 Not used. 9 Not used.		r that takes th	ie DCO outpu	t f _{OSC} as its c	clock input.	
4:0	N1_7PPM[6	Sets v gal oc N1 re divide 00000	ld divider valu gister can be	OUT output d les will be rou calculated by	nded up to th taking the div	d values are [e nearest eve vider ratio mir N1 registers.	n value. The nus one. For e	value for the	

Register 14. Reference Frequency

Bit	D7	D6	D5	D5 D4 D3 D2 D1					
Name	N1_7P	PM[1:0]	RFREQ_7PPM[37:32]						
Туре	R/W		R/W						



Bit	Name	Function
7:6	N1_7PPM[1:0]	CLKOUT Output Divider.
		Sets value for CLKOUT output divider. Allowed values are $[1, 2, 4, 6,, 2^7]$. Illegal odd divider values will be rounded up to the nearest even value. The value for the N1 register can be calculated by taking the divider ratio minus one. For example, to divide by 10, write 0001001 (9 decimal) to the N1 registers. 0000000 = 1 $1111111 = 2^7$
5:0	RFREQ_7PPM[37:32]	Reference Frequency.
		Frequency control input to DCO.

Register 15. Reference Frequency

Bit	D7	D6	D5	D4	D3	D2	D1	D0		
Name)	RFREQ_7PPM[31:24]								
Туре	R/W									
Bit	Name)			Functi	ion				
7:0	RFREQ_7PP		Reference Frequency. Frequency control input to DCO.							

Register 16. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0								
Name	9			RFREQ_7	PPM[23:16]					
Туре	R/W									
Bit	Name	Name Function								
7:0	RFREQ_7PP	VI[23:16] Re	Reference Frequency.							
		Fre	Frequency control input to DCO.							

Register 17. Reference Frequency

Bit	D7	D6	D5	D4	D3	D2	D1	D0		
Name	RFREQ_7PPM[15:8]									
Туре		R/W								



Bit	Name	Function
7:0	RFREQ_7PPM[15:8]	Reference Frequency.
		Frequency control input to DCO.

Register 18. Reference Frequency

Bit	D7	D7 D6 D5 D4 D3 D2 D1 D0									
Name	•	RFREQ_7PPM[7:0]									
Туре		R/W									
Bit	Name	Name Function									
7:0	RFREQ_7PP		7:0] Reference Frequency.								
		Frequency control input to DCO.									



Register 135. Reset/Freeze/Memory Control

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	RST_REG	NewFreq	Freeze M	Freeze VCADC	N/A		RECALL	
Туре	R/W	R/W	R/W	R/W	R/W		R/W	

Reset settings = 00xx xx00

Bit	Name	Function
7	RST_REG	Internal Reset.
		0 = Normal operation.
		1 = Reset of all internal logic. Output tristated during reset.
		Upon completion of internal logic reset, RST_REG is internally reset to zero.
		Note: Asserting RST_REG will interrupt the I ² C state machine. It is not the recommended approach for starting from initial conditions.
6	NewFreq	New Frequency Applied.
		Alerts the DSPLL that a new frequency configuration has been applied. This bit will
		clear itself when the new frequency is applied.
5	Freeze M	Freezes the M Control Word.
		Prevents interim frequency changes when writing RFREQ registers.
4	Freeze	Freezes the VC ADC Output Word.
	VCADC	May be used to hold the nominal output frequency of an Si571.
3:1	N/A	Always Zero.
0	RECALL	Recall NVM into RAM.
		0 = No operation.
		1 = Write NVM bits into RAM. Bit is internally reset following completion of operation.
		Note: Asserting RECALL reloads the NVM contents in to the operating registers without interrupting the I ² C state machine. It is the recommended approach for starting from initial conditions.

Register 137. Freeze DCO

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name				Freeze DCO				
Туре				R/W				

Reset settings = 00xx xx00

Bit	Name	Function
7:5	Reserved	
4	Freeze DCO	Freeze DCO. Freezes the DSPLL so the frequency configuration can be modified.
3:0	Reserved	



5. Si570 (XO) Pin Descriptions

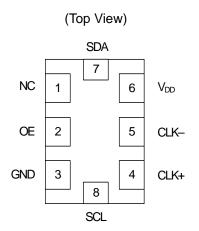


Table 14. Si570 Pin Descriptions

Pin	Name	Туре	Function
1	NC	N/A	No Connect. Make no external connection to this pin.
2	OE	Input	Output Enable: See "7. Ordering Information" on page 31.
3	GND	Ground	Electrical and Case Ground.
4	CLK+	Output	Oscillator Output.
5	CLK– (NC for CMOS*)	Output (N/A for CMOS*)	Complementary Output. (NC for CMOS*).
6	V _{DD}	Power	Power Supply Voltage.
7	SDA	Bidirectional Open Drain	I ² C Serial Data.
8	SCL	Input	I ² C Serial Clock.
*Note: CMOS output option only: make no external connection to this pin.			



6. Si571 (VCXO) Pin Descriptions

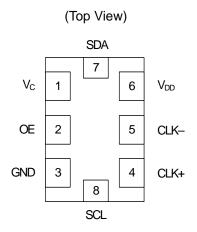


Table 15. Si571 Pin Descriptions

Pin	Name	Туре	Function
1	V _C	Analog Input	Control Voltage
2	OE	Input	Output Enable: See "7. Ordering Information" on page 31.
3	GND	Ground	Electrical and Case Ground
4	CLK+	Output	Oscillator Output
5	CLK– (NC for CMOS*)	Output (N/A for CMOS*)	Complementary Output. (NC for CMOS*).
6	V _{DD}	Power	Power Supply Voltage
7	SDA	Bidirectional Open Drain	I ² C Serial Data
8	SCL	Input	I ² C Serial Clock
*Note: CMOS output option only: make no external connection to this pin.			



7. Ordering Information

The Si570/Si571 supports a wide variety of options including frequency range, start-up frequency, temperature stability, tuning slope, output format, and V_{DD} . Specific device configurations are programmed into the Si570/Si571 at time of shipment. Configurations are specified using the Part Number Configuration chart shown below. Silicon Labs provides a web browser-based part number configuration utility to simplify this process. Refer to www.siliconlabs.com/VCXOPartNumber to access this tool and for further ordering instructions. The Si570/Si571 XO/VCXO series is supplied in an industry-standard, RoHS compliant, 8-pad, 5 x 7 mm package. Tape and reel packaging is an ordering option.

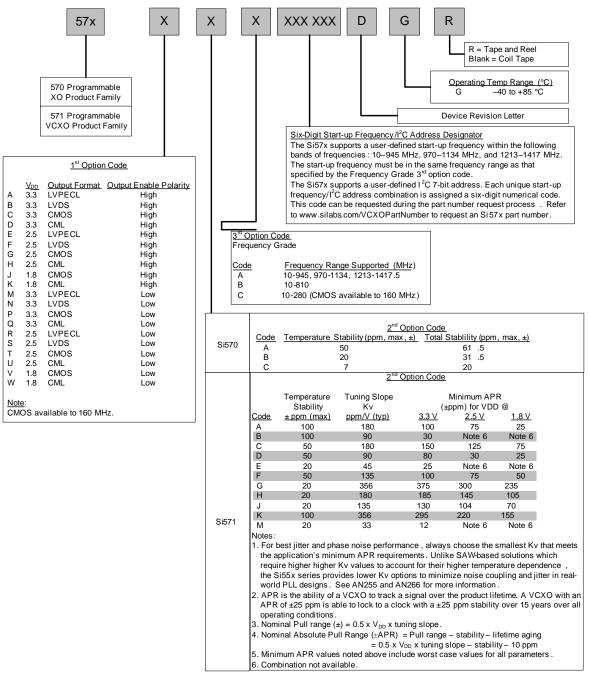


Figure 6. Part Number Convention



8. Si57x Mark Specification

Figure 7 illustrates the mark specification for the Si57x. Table 16 lists the line information.

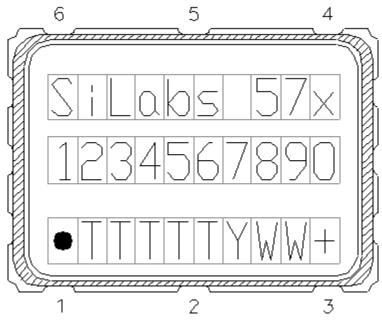


Figure 7. Mark Specification

Table 16. Si57x Top Mark Description

Line	Position	Description	
1	1–10	"SiLabs"+ Part Family Number, 57x (First 3 characters in part number where $x = 0$ indicates a 570 device and $x = 1$ indicates a 571 device)	
2	1–10	Si570, Si571: Option1 + Option2 + Option3 + ConfigNum(6) + Temp	
3	Trace Code		
	Position 1	Pin 1 orientation mark (dot)	
	Position 2	Product Revision (D)	
Position 3–6 Tiny Trace Code (4 alphanumeric characters per assemb		Tiny Trace Code (4 alphanumeric characters per assembly release instructions)	
Position 7 Year (least significant year digit), to be assi		Year (least significant year digit), to be assigned by assembly site (ex: 2007 = 7)	
	Position 8–9 Calendar Work Week number (1–53), to be assigned by assemble		
Position 10 "+" to indicate Pb-Free a		"+" to indicate Pb-Free and RoHS-compliant	



9. Outline Diagram and Suggested Pad Layout

Figure 8 illustrates the package details for the Si570/Si571. Table 17 lists the values for the dimensions shown in the illustration.

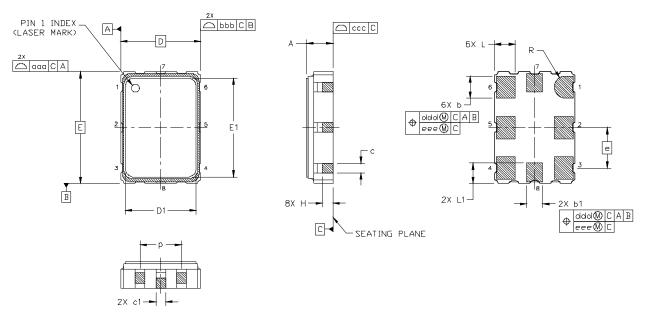


Figure 8. Si570/Si571 Outline Diagram

Table 17. Package Diagram Dimensions (mm)

	• •		,
Dimension	Min	Nom	Max
А	1.50	1.65	1.80
b	1.30	1.40	1.50
b1	0.90	1.00	1.10
С	0.50	0.60	0.70
c1	0.30	_	0.60
D		5.00 BSC	
D1	4.30	4.40	4.50
е	2.54 BSC		
E		7.00 BSC	
E1	6.10	6.20	6.30
Н	0.55	0.65	0.75
L	1.17	1.27	1.37
L1	1.07	1.17	1.27
р	1.80	—	2.60
R	0.70 REF		
aaa	—	—	0.15
bbb	bbb — — 0.15		
CCC	—	—	0.10
ddd	—	—	0.10
eee	—	—	0.05
 Note: 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994. 			



10. 8-Pin PCB Land Pattern

Figure 9 illustrates the 8-pin PCB land pattern for the Si570/Si571. Table 18 lists the values for the dimensions shown in the illustration.

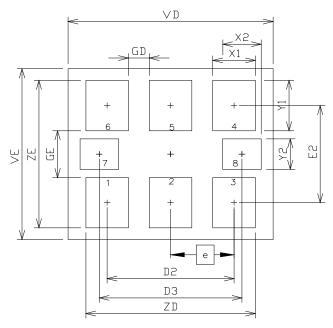


Figure 9. Si570/Si571 PCB Land Pattern

Table 18. PCB Land Pattern Dimensions (mm)

Dimension	Min	Max	
D2	5.08 REF		
D3	5.705	5 REF	
е	2.54 BSC		
E2	4.20	REF	
GD	0.84	—	
GE	2.00 —		
VD	8.20 REF		
VE	7.30 REF		
X1	1.70 TYP		
X2	1.545 TYP		
Y1	2.15 REF		
Y2	1.3 REF		
ZD	— 6.78		
ZE	—	6.30	

Note:

- **1.** Dimensioning and tolerancing per the ANSI Y14.5M-1994 specification.
- 2. Land pattern design follows IPC-7351 guidelines.
- **3.** All dimensions shown are at maximum material condition (MMC).

Rev. 1.6

4. Controlling dimension is in millimeters (mm).



REVISION HISTORY

Revision 1.6

June, 2018

• Changed "Trays" to "Coil Tape" in "7. Ordering Information" on page 31.

Revision 1.5

• Added Section 3.2 and 3.3.

Revision 1.4

• Added Table 12, "Thermal Characteristics," on page 12.

Revision 1.3

- Updated Table 3 on page 5 to include 7 ppm temperature stability and 20 ppm to stability parameters. Also
 changed aging test condition (frequency drift over life) from 15 years to 20 years.
- Updated 2.5 V/3.3 V and 1.8 V CML output level specification for Table 4 on page 6.
- Added footnotes clarifying max offset frequency test conditions in Table 5 on page 7.
- Updated ESD HBM sensitivity rating and the JEDEC standard in Note 2 in Table 13 on page 13.
- Updated Table 10 on page 11 to include "Moisture Sensitivity Level" and "Contact Pads" rows.
- Added Si570 7 ppm Total Stability Ordering Option to Figure 6 on page 31.
- Updated Figure 7 and Table 16 on page 32 to reflect specific marking information. Previously, Figure 7 was generic.
- Clarified "3.1.2. Reconfiguring the Output Clock for Large Changes in Output Frequency" on page 15 and added new registers 13-18 in "4. Serial Port Registers" on page 22 for the Si570 7 ppm temperature stability / 20 ppm total stability ordering option.
- Added text to "3. Functional Description" on page 14, paragraph 1, to state that the total output jitter complies to and exceeds strict requirements of various high-speed communication systems.

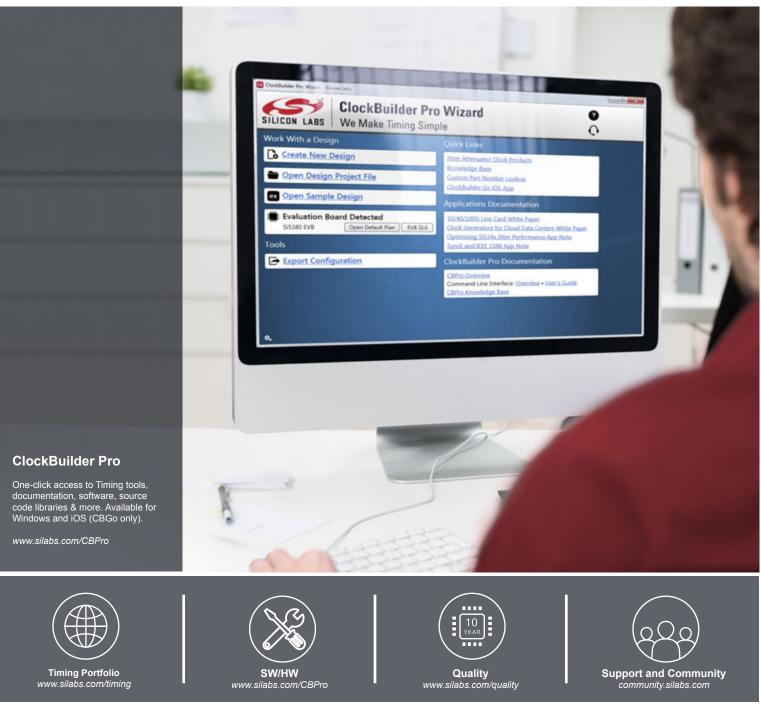
Revision 1.2

- Replaced "Unfreeze to Newfreq Delay" with the clearer terminology "Unfreeze to Newfreq Timeout" on page 15 and in Table 11 on page 12.
- Added Freeze M procedure on page 14 for preventing output clock changes during small frequency change multi-register RFREQ writes.
- Added Freeze M, Freeze VCADC, and RST_REG versus RECALL information to Register 135 references in "4. Serial Port Registers" on pages 17 and 20.
- Added Si570 20 ppm Total Stability Ordering Option to Figure 6 on page 31.
- Updated Figure 8 and Table 17 on page 33 to include production test sidepads. This change is for reference only as the sidepads are raised above the seating plane and do not impact PCB layout.
- Corrected errors in Table 10 on page 11.

Revision 1.1

- Restored programming constraint information on page 15 and in Table 12, page 12.
- Clarified NC (No Connect) pin designations in Tables 13–14 on pages 22–23.





Disclaimer

Silicon Labs intends to provide customers with the latest, accurate, and in-depth documentation of all peripherals and modules available for system and software implementers using or intending to use the Silicon Labs products. Characterization data, available modules and peripherals, memory sizes and memory addresses refer to each specific device, and "Typical" parameters provided can and do vary in different applications. Application examples described herein are for illustrative purposes only. Silicon Labs reserves the right to make changes without further notice and limitation to product information, specifications, and descriptions herein, and does not give warranties as to the accuracy or completeness of the included information. Silicon Labs shall have no liability for the consequences of use of the information supplied herein. This document does not imply or express copyright licenses granted hereunder to design or fabricate any integrated circuits. The products are not designed or authorized to be used within any Life Support System without the specific vitten consent of Silicon Labs. A "Life Support System" is any product or system intended to support or sustain life and/or health, which, if it fails, can be reasonably expected to result in significant personal injury or death. Silicon Labs products are not designed or authorized for military applications. Silicon Labs products shall under no circumstances be used in weapons of mass destruction including (but not limited to) nuclear, biological or chemical weapons, or missiles capable of delivering such weapons.

Trademark Information

Silicon Laboratories Inc.®, Silicon Laboratories®, Silicon Labs®, SiLabs® and the Silicon Labs logo®, Bluegiga®, Bluegiga®, Bluegiga Logo®, Clockbuilder®, CMEMS®, DSPLL®, EFM®, EFM32®, EFR, Ember®, Energy Micro, Energy Micro logo and combinations thereof, "the world's most energy friendly microcontrollers", Ember®, EZLink®, EZRadio®, EZRadio®, EZRadio®, SiPHY®, Telegesis, the Telegesis Logo®, USBXpress®, Zentri, Z-Wave, and others are trademarks or registered trademarks of Silicon Labs. ARM, CORTEX, Cortex-M3 and THUMB are trademarks or registered trademarks of ARM Holdings. Keil is a registered trademark of ARM Limited. All other products or brand names mentioned herein are trademarks of their respective holders.



Silicon Laboratories Inc. 400 West Cesar Chavez Austin, TX 78701 USA

http://www.silabs.com

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Programmable Oscillators category:

Click to view products by Silicon Labs manufacturer:

Other Similar products are found below :

8N4Q001LG-0102CDI 8N4Q001LG-0139CDI DSC8101AL2 8N0Q001BH-2202CDI DSC8101DI5 DSC8121AI5 EP16E7E2H26.000MTR SIT8102AI-13-18E-25.00000T 8N4Q001LG-1033CDI DSC8121CL5T DS1090U-2/V+T DS1090U-32+T DSC8121AM2 DSC8001AL2 DSC8101BL2 DSC8121CI1 DSC8124CI5 DSC8003CI2T DSC8102DI2 DSC8124CI2 DSC8123CI5 DSC8124BI2 DSC8122BI5 DSC8101DI2 DSC8121CL5 SG-8002JA 20.000M-PTMB-ROHS ECS-P143-10-AN 570FCC001204DG 570FCC000169DG 544BAEB002025CBG 544BAHB002172BBGR 544BAHB002157BBGR DS1077LU-40+T SiT3808AI-D2-XXXX-000.FP000X DS1090U-1+T DS1086Z+T&R DS1087LU-447+T 544BCAA000112BBG DS1086LU+T 564BACA001478ABG SG-8018CG-PWT BLANK SG-8002CA 2.4576M-PCBB 564BACA000121ABG 564BACA001478BBG 564BABA002053ABG 564BAAA000121ABG 564BAAC000115BBG 564BAAD000115BBG ECS-P8F3X-1.000-AN 570CBC000306DG